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# Thermoelectric properties of silicon hexaboride prepared by spark plasma sintering method

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Silicon hexaboride is attractive for various industrial applications because of its high temperature capability, high hardness and excellent electrical conductivity, in particular it is a promising material for use as a thermoelectric semiconductor at high temperature. We have used a spark plasma sintering technique to produce silicon hexaboride ceramics. The Seebeck coefficient, electrical conductivity and thermal conductivity were measured and the effect of additives, phase composition and microstructure on the thermoelectric properties were discussed. The approximate value of Z (figure of merit value) of the SPS specimen reached about  $9.6 \times 10^{-6}$ /K at 1273 K. The thermoelectric properties (Z) of the SPS specimen are improved in comparison with the specimen by hot-pressing. The effect of the addition of lanthanum and boron on thermoelectric properties of SiB<sub>6</sub> were also evaluated.

Key words: spark plasma sintering(SPS), silicon hexaboride(SiB<sub>6</sub>), thermoelectric, Seebeck Coefficient.

#### Introduction

Silicon borides  $(Si_XB_Y)$  are attractive in various industrial application because of their high temperature properties, high hardness and excellent electrical conductivity. Of several  $Si_XB_Y$  phases which were previously reported,  $SiB_6$  phase is a promising material for use as a thermoelectric semiconductor at high temperature [1] because it has a large Seebeck coefficient, low thermal conductivity, excellent electrical conductivity, high hardness [1, 2]. However, the application of  $SiB_6$ has been limited by the poor sinterability using conventional sintering technique.

Spark plasma sintering (SPS) is one of the best candidates to fully densify materials that are otherwise poorly sinterable materials. The SPS technique is a newly developed sintering process that can heat the material several to tens of thousands of degrees Celsius by spark discharges between the particles. The spark discharges are generated by a pulsed direct current applied through electrodes. Due to these discharges, acceleration of mass-transfer occurs by the evaporation or melting on the particle surface and the densification can be achieved rapidly at lower overall temperatures. Therefore, the SPS process can control the grain growth by using a shorter sintering time than that of the conventional process, such as hot-pressing and hotisostatic pressing [3-5]. The thermoelectric of figure of merit, Z is mostly influenced by the thermoelectric power through the S<sup>2</sup> term in Z=S<sup>2</sup> $\sigma$ T/ $\kappa$  (S: Seebeck coefficient;  $\sigma$ : electrical conductivity;  $\kappa$ : thermal conductivity). This work presents the mechanism for sintering of SiB<sub>6</sub> by spark plasma sintering to improve the microstructure for thermoelectric applications at high temperature. We report the thermoelectric property changes after addition of lanthanum or boron.

# **Experimental Procedure**

Commercially available SiB<sub>6</sub> powder was used as starting material. Densification was performed by the spark plasma sintering system (Sumitomo Coal Mining: SPS-515S). The processing was carried out in a vacuum at 1200-1600°C for 5minutes in a 10 mm diameter graphite die. The phases of the initial powders and sintered bodies were identified using a X-ray diffraction (XRD). The particle size distribution was measured by a particle size analyzer (Microtrac-x100). The relative density of sintered bodies was determined using the Archimedes method and scanning electron microscope (JEOL: JSM-5900LV). The mixing of lanthanum or boron were carried out in glove box for 6 hours. Firstly weights of SiB<sub>6</sub> powder and additive were measured accurately, then it was stirred in a mortar under Ar-atmosphere. Microstructure and phase distribution were observed by a electron probe X-ray micro analyzer (EPMA) (JEOL: JXA-8900R). SiB<sub>6</sub> specimens were cut out for the electrical conductivity and Seebeck coefficient measurements. Electrical conductivity was measured using a D.C. four-probe method

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under Ar-5% $H_2$  atmosphere. The Seebeck coefficient was measured from 573 K to 1273 K. Specimens were heated over a small temperature range by a substrate-heater and the electro-motive force was measured using a digital multimeter.

# **Results and Discussion**

The powders are typically irregular and plate-like in shape and have a bimodal size distribution. Their average size is about 2.3  $\mu$ m.

Figure 1 shows the typical X-ray diffraction pattern of sintered bodies of pure  $SiB_6(a)$  and 3 wt% La-doped  $SiB_6(b)$ . The pure  $SiB_6$  sintered body consists mainly of  $SiB_6$  with a small amount of  $SiB_4$  and  $Si_XB_Y$  phases detected. In the case of the La-doped specimen, most of the peaks became sharper, indicating that the addition of lanthanum improves the crystallinity of the sintered body.

Relative densities of the sintered specimens as a function of temperature are represented in Fig. 2. The sintered density increases with increasing sintering



Fig. 1. X-ray diffraction patterns of the SiB<sub>6</sub> powder and sintered bodies.



Fig. 2. Variation of the relative densities with temperature.

temperature. In the case of pure  $SiB_6$  powder, the sintered body reached 98% relative density even at 1500°C and was fully densified at 1600°C. In the case of 3 wt% La doped SiB<sub>6</sub>, the sintered body reached 97% theoretical density at 1400°C and completed the densification at 1500°C. However, some melting in the disc specimen was observed over 1600°C, indicating the proof of localized melting during the SPS process.

In the Si-B binary system, there are many compounds such as  $SiB_4$  (rhombohedral),  $SiB_6$  (orthorhombic) and  $SiB_n$  (hexagonal, n=14-49) [6, 8]. Among them,  $SiB_4$ has a low thermal conductivity and high electrical conductivity but a low seebeck coefficient [9]. On the other hand, SiB<sub>6</sub> and SiB<sub>n</sub> have large Seebeck coefficients, low thermal conductivities and a moderately low electrical conductivities. Therfore, control over the the phase distribution in material which is nominally SiB<sub>6</sub> will affect thermoelectric properties. The thermoelectric properties of spark plasma sintered B-doped SiB<sub>6</sub> specimen containing 90 at% B had the largest values [2]. Figure 3 shows the microstructure and phase distribution of an SPS-processed specimen. The EPMA results showed that the overall structure is mainly composed of  $SiB_6$  phase (grey contrast) with a small amount of SiB<sub>4</sub> (white contrast) and Si<sub>X</sub>B<sub>Y</sub> (black contrast) phases homogeneously distributed. The overall boron content in the raw materials was 87%. Therefore, addition of boron provides some possibility of improving of thermoelectric property.

Figure 4(a) shows the temperature dependence of the Seebeck coefficients (S) of SiB<sub>6</sub>. The S values increase with increasing temperature. The Seebeck coefficient of pure SiB<sub>6</sub> sintered at 1600°C changed from  $8.7 \times 10^{-5}$  to  $240 \times 10^{-6}$  V/K in the temperature range 300 K to 1273 K. The SPS specimens have higher Seebeck coefficients than the specimen prepared by hotpressing. Figure 4(b) shows the Seebeck coefficients for La-doped SiB<sub>6</sub> and boron-doped SiB<sub>6</sub>. The Seebeck coefficient of 3 wt% La-doped specimen was decreased. The B-doped specimen had an improved Seebeck



Fig. 3. Microstructure and chemical composition the body sintered at 1600°C.



Fig. 4. Temperature dependence of Seebeck Coefficients of SiB<sub>6</sub>.

coefficient (about  $315 \times 10^{-6}$  V/K at 1273 K). In the case of 7 wt% Boron-doped specimens, the Seebeck coefficient value was decreased significantly at temperatures greater than 1000 K.

The temperature dependences of electrical conductivity in  $SiB_6$  is shown in Fig 5. The electrical conductivity of  $SiB_6$  sintered bodies increased with increasing



Fig. 5. Temperature dependence of electrical conductivity of SiB<sub>6</sub>.

temperature for all the specimens. The electrical conductivity of the pure SiB<sub>6</sub> specimen was  $0.6 \times 10^3$  S/m at 1273 K. In the case of 3 wt% La-doped specimens, the electrical conductivity was lower,  $0.4 \times 10^3$  S/m at 1273 K. On the contrary, in the case of 5 wt% boron-doped specimens, the electrical conductivity increased to  $0.8 \times 10^3$  S/m at 1273 K.

# Conclusion

Pure SiB<sub>6</sub> was successfully densified by a spark plasma sintering technique, reaching above 99% relative density at 1600°C. In case of 3 wt% La-doped SiB<sub>6</sub>, the relative density reached about 97% at 1400°C and over 99% at 1500°C. The Seebeck coefficient of pure SiB<sub>6</sub> sintered at 1600°C, changed from  $-8.7 \times 10^{-5}$  to  $240 \times 10^{-6}$  V/K in the temperature range 300 K to 1273 K. The electrical conductivity of the pure  $SiB_6$  specimen was  $0.6 \times 10^3$  S/m at 1273 K. The approximated figure of merit value, Z, of the SPS specimen reached about 9.6×10<sup>-6</sup>/K at 1273 K. Therefore, the thermoelectric properties, ZT, of the SPS specimen were improved in comparison with the specimen prepared by hot-pressing. In the La-doped samples, the Seebeck coefficient and electrical conductivity were decreased. The thermoelectric properties of boron-doped specimens were improved. These thermoelectric properties are useful to evaluate the suitability of the thermoelectric materials.

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